PCN Number:			20	20190819001.2						C N	Date:	Aug 28, 2019		
Title: Qualification			of FM0055 Leadframe for Select VSSOP Package Devices											
Cus	tomer	Contact:	<u>PC</u>	N Manag	<u>er</u>	De	pt:	Quality Servi	ces					
Pro	posed	1 st Ship Dat	te: Feb 28, (See No		a, 2020 Est		Estir Avai	imated Sample iilability:		Date Provided at Sample request				
Cha	nge T	ype:			-									
	Asser	nbly Site		Desi				ก			Wafer Bump Site			
	Asser	nbly Process			닏	Data Sheet				Wafer Bump Material				
	Asser	nbly Material	S S		H	Part number change				Wafer Fab Site				
	Packi	anical Specifi ng/Shipping/			┟╞┽	Test Brasses				\square	Wafer	Fab Matorials		
	FACKI	ng/snipping/	Laut	ang		IE	SUFIU	CE55	<u>s</u>			Fab Process		
						Ρ	CN [Details			Turci			
Des	criptio	on of Change	e:			-								
Texa VSS	Texas Instruments Incorporated is announcing the qualification of FM0055 Leadframe for Select VSSOP package devices listed in the "Product Affected" Section.													
				Cu	rren	t		New						
				FM	0014	1		FM0055						
	Leadframe p/n			(F	<u>'EH)</u>		1	(HDS)						
	Lead	i finisn		Non-roughened				Roughened (1	ор	sia	e)			
Reason for Change:														
Continuity of supply.														
Not	Note 1: Unexpected discontinuation of operation for PEH Hong Kong leadframe supplier. Current													
lead	leadframe material inventory is expected to support shipments through February 2020. To avoid													
Sale	Sales Representative or to the PCN Team (PCN, www.admin_team@list_ti.com)													
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):														
None														
Anticipated impact on Material Declaration														
\square	No Impact to the Attended Atte													
Material Declaration production data and will be						a and will be av	aila	able	e followii	ng the production				
	release. Upon production release the revised reports can be							d reports can be						
	obtained from the <u>11 Eco-Info website</u> . There is no impact to t								e is no impact to the					
with this PCN change.									nce requirements					
Changes to product identification resulting from this PCN:														
None														
Product Affected:														
OP	OPA2333AQDGKRQ1 TMP411AQDGKRQ1 TMP411DQDGKRQ1													

Qualification Report Approved 21-May-2019

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Spec	n Lo t Qt y	S S/ Lo t	Test Name / Condition	Duration	Qual Device: TMP411DQDGK RQ1	Qual Device: TPS61085TDGK RQ1	QBSDevice: TPS79801QDGN RQ1
PC	A1	JEDEC J- STD-020 JESD22- A113	3	77	Auto Preconditioning	Level 3 - 260C	3/231/0	3/231/0	-
PC	A1	JEDEC J- STD-020 JESD22- A113	3	77	Auto Preconditioning	Level 2 - 260C	-	-	3/462/0
AC	A3	JEDEC JESD22- A102	3	77	Autoclave, 121C	96 Hours	-	-	3/231/0
тс	A4	JEDEC JESD22- A104 & Appendix 3	3	77	Temperature Cycle, -65/150C	500 Cycles	3/231/0	3/231/0	3/231/0
TC- WBP	A4	MIL- STD883 Method 2011	1	60	Auto Post TC Bond Pull	Wires	3/90/0	3/90/0	3/90/0
PTC	A5	JEDEC JESD22- A105	1	45	Power Temperature Cycle	1000 Cycles	N/A	N/A	N/A
HTOL	B1	JEDEC JESD22- A108	3	77	Life Test, 125C	1000 Hours	N/A	N/A	N/A
ELFR	B2	AEC Q100-008	3	77	Early Failure Rate, 125C	48 Hours	N/A	N/A	N/A
EDR	В3	AEC Q100-005	3	77	NVM Endurance, Data Retention, Operational Life	-	N/A	N/A	N/A
WBS	C1	AEC Q100-001	1	30	Wire Bond Shear (Cpk>1.67)	-	-	-	3/90/0
WBP	C2	MIL- STD883 Method 2011	1	30	Wire Bond Pull (Cpk>1.67)	Wires	3/228/0	3/228/0	3/228/0
SD	C3	JEDEC JESD22- B102	1	15	Surface Mount Solderability (Pb)	>95% Lead Coverage 8 Hours Steam Age	-	3/45/0	3/45/0
SD	СЗ	JEDEC JESD22- B102	1	15	Surface Mount Solderability (Pb- Free)	>95% Lead Coverage 8 Hours Steam Age	-	3/45/0	3/45/0

Туре	#	Test Spec	Mi n Lo t Qt y	S S/ Lo t	Test Name / Condition	Duration	Qual Device: TMP411DQDGK RQ1	Qual Device: TPS61085TDGK RQ1	QBSDevice: TPS79801QDGN RQ1
PD	C4	JEDEC JESD22- B100 and B108	3	10	Auto Physical Dimensions	Devices (Cpk>1.67)	-	3/30/0	3/30/0
LI	C6	JEDEC JESD22- B105	1	50	Lead Integrity	# of leads to destruction	-	-	3/72/0
				1		1			
EM	D1	JESD61	-	-	Electro migration	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
TDDB	D2	JESD35	-	-	Time Dependent Dielectric Breakdown	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
нсі	D3	JESD60 & 28	-	-	Hot Injection Carrier	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
NBTI	D4	-	-	-	Negative Bias Temperature Instability	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
SM	D5	-	-	-	Stress Migration	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements
DS	G7	MIL-STD- 883 Method 2019	1	5	Die Shear	Die	3/30/0	3/30/0	3/30/0
	1								
MQ			-	-	Manufacturability (Auto Assembly)	(per automotive requirements)	3/Pass	3/Pass	3/Pass
MSL			-	-	Moisture Sensitivity	Level 2 - 260C	-	-	3/36/0
MSL			-	-	Moisture Sensitivity	Level 3 - 260C	3/36/0	3/36/0	
XRAY			-	-	X-Ray	Top side only	3/15/0	3/15/0	3/15/0
YLD			-	-	FTY & Bin Summary	-	3/Pass	3/Pass	3/Pass

- QBS: Qual By Similarity

- Qual Device TMP411DQDGKRQ1 is qualified at LEVEL3-260C

- Qual Device TPS61085TDGKRQ1 is qualified at LEVEL3-260C

- QBS Device TPS79801QDGNRQ1 is qualified at LEVEL2-260C

A1 (PC): Preconditioning: Performed for THB, Biased HAST, AC, uHAST, TC & PTC samples, as applicable.

Ambient Operating Temperature by Automotive Grade Level: Grade 0 (or E): -40°C to +150°C Grade 1 (or Q): -40°C to +125°C Grade 2 (or T): -40°C to +105°C Grade 3 (or I) : -40°C to +85°C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level): Room/Hot/Cold : HTOL, ED Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU Room : AC/uHAST

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

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